

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		Page 1 of 1
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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	E	US-			
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	G	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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	N	JP 2003-286369	10-2003	Japan	Watanabe et al.	C08L 21/00
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NON-PATENT DOCUMENTS

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	U	JP 2003-286369 (10-2003) abstract and translation in English
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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